# M5M5256DFP, VP-55LL, -70LL, -70LLI,

-55XL,-70XL

262144-BIT (32768-WORD BY 8-BIT) CMOS STATIC RAM

#### **DESCRIPTION**

The M5M5256DFP, VP is 262,144-bit CMOS static RAMs organized as 32,768-words by 8-bits which is fabricated using high-performance 3 polysilicon CMOS technology. The use of resistive load NMOS cells and CMOS periphery results in a high density and low power static RAM. Stand-by current is small enough for battery back-up application. It is ideal for the memory systems which require simple interface.

Especially the M5M5256DVP are packaged in a 28-pin thin small outline package.

#### **FEATURE**

	Access	Oprating	Power supply current			
Ту ре	time (max)	Temperature	Active (max)	Stand-by (max)		
M5M5256DFP,VP-55LL M5M5256DFP,VP-70LL	55ns 70ns	0~70°C		20µA (Vcc=5.5V)		
M5M5256DFP,VP-70LLI	70ns	-40~85°C	50mA (Vcc=5.5V)	40μA (Vcc=5.5V)		
M5M5256DFP,VP-55XL M5M5256DFP,VP-70XL	55ns 70ns	0~70°C		5μA (Vcc=5.5V) 0.05μA (Vcc=3.0V, Typical)		

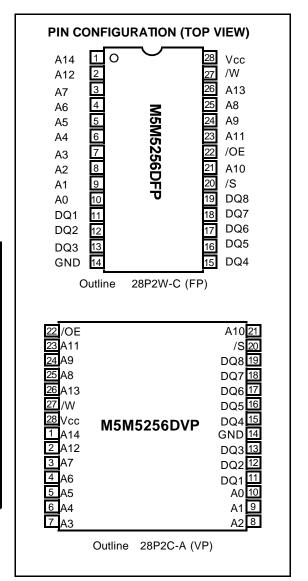
- •Single +5V power supply
- •No clocks, no refresh
- •Data-Hold on +2.0V power supply
- •Directly TTL compatible : all inputs and outputs
- •Three-state outputs : OR-tie capability
- •/OE prevents data contention in the I/O bus
- •Common Data I/O
- •Battery backup capability
- •Low stand-by current ...... 0.05µA(typ.)

#### **PACKAGE**

M5M5256DFP : 28 pin 450 mil SOP M5M5256DVP : 28pin 8 X 13.4 mm TSOP

### **APPLICATION**

Small capacity memory units





**RENESAS LSIs** 

# M5M5256DFP,VP-55LL,-70LL,-70LLI, -55XL,-70XL

262144-BIT (32768-WORD BY 8-BIT) CMOS STATIC RAM

#### **FUNCTION**

The operation mode of the M5M5256DFP,VP is determined by a combination of the device control inputs /S, /W and /OE. Each mode is summarized in the function table.

A write cycle is executed whenever the low level /W overlaps with the low level /S. The address must be set up before the write cycle and must be stable during the entire cycle. The data is latched into a cell on the trailing edge of /W, /S, whichever occurs first, requiring the setup and hold time relative to these edge to be maintained. The output enable /OE directly controls the output stage. Setting the /OE at a high level,the output stage is in a high-impedance state, and the data bus contention problem in the write cycle is eliminated.

A read cycle is executed by setting /W at a high level and /OE at a low level while /S are in an active state.

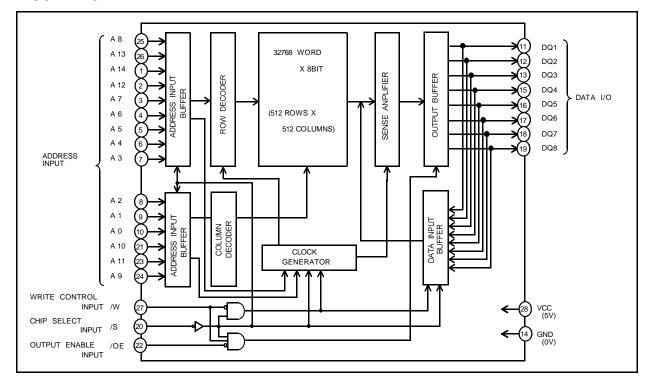
When setting /S at a high level, the chip is in a non-selectable mode in which both reading and writing are disabled. In this mode, the output stage is in a high-impedance state, allowing OR-tie with other chips and memory expansion by /S. The power supply current is reduced as low as the stand-by current which is specified as lcc3 or lcc4, and the memory data can be held at +2V power supply, enabling battery back-up operation during power failure or power-down operation in the non-selected mode.

#### **FUNCTION TABLE**

/S	/W	/OE	Mode	DQ	Icc
Н	Х	Х	Non selection	High-impedance	Stand-by
L	L	Х	Write	DIN	Activ e
L	Н	L	Read	Dоит	Activ e
L	Н	I		High-impedance	Activ e

Note • "H" and "L" in this table mean VIH and VIL, respectively.

#### **BLOCK DIAGRAM**





<sup>• &</sup>quot;X" in this table should be "H" or "L".

# M5M5256DFP, VP-55LL, -70LL, -70LLI, -55XL,-70XL 262144-BIT (32768-WORD BY 8-BIT) CMOS STATIC RAM

#### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Conditions	Ratings	Unit
Vcc	Supply voltage		-0.3*~7.0	V
Vı	Input voltage	With respect to GND	-0.3*~Vcc+0.3 (Max 7.0)	V
Vo	Output voltage		0~Vcc	V
Pd	Power dissipation	Ta=25°C	700	mW
Topr	Operating temperature	-LL,-XL	0~70	00
I opr	Operating temperature	-LLI	-40~85	°C
T <sub>stg</sub>	Storage temperature		-65~150	°C

<sup>\* -3.0</sup>V in case of AC ( Pulse width < 30ns )

### DC ELECTRICAL CHARACTERISTICS (Vcc=5V±10%, unless otherwise noted)

0	D	<b>T</b>			Limits			
Symbol	Parameter	Test condi	tions		Min	Тур	Max	Unit
VIH	High-level input voltage				2.2		Vcc +0.3	V
VIL	Low-level input voltage				-0.3*		0.8	V
V <sub>OH1</sub>	High-level output voltage 1	Iон=-1mA			2.4			V
V <sub>OH2</sub>	High-level output voltage 2	Iон=-0.1mA			Vcc -0.5			V
Vol	Low-level output voltage	loL=2mA					0.4	V
lı	Input current	V <sub>1</sub> =0~Vcc					±1	μΑ
lo	Output current in off-state	/S=Vih or or /OE=Vih, Vi/o=0~Vcc					±1	μΑ
	Icc1 Active supply current (AC, MOS level)	/S<0.2V,	55ns		30	45		
lcc1		Other inputs<0.2V or	V 70ns		25	40	mA	
		Output-open 1M				2	4	
		/S=VıL,	55ns		30	50		
lcc2	Active supply current (AC, TTL level)	other inputs=VIH or VII	70ns		25	45	mA	
	(**************************************	Output-open	1MHz		4	8		
			~25°C	-LL,-LLI			2	
			~25 C	-XL		0.1	0.4	
		(0. )/ 0.0)/	~40°C	-LL,-LLI			6	
Icc3	Stand-by current	/S>Vcc-0.2V,	~40 C	-XL			1.2	μΑ
		other inputs=0~Vcc	~70°C	-LL,-LLI			20	
			7700	-XL			5	
		~85°C		-LLI			40	
Icc4	Stand-by current	/S=V <sub>IH</sub> ,other inputs=0	~Vcc				3	mA

<sup>\* -3.0</sup>V in case of AC ( Pulse width < 30ns )

### **CAPACITANCE** ( Vcc=5V±10%, unless otherwise noted)

			Limits		Limits		11.2
Symbol	Parameter	Test conditions	Min	Тур	Max	Unit	
Cı	Input capacitance	V <sub>1</sub> =GND, V <sub>1</sub> =25mVrms, f=1MHz			6	pF	
Co	Output capacitance	Vo=GND, Vo=25mVrms, f=1MHz			8	pF	

Note 0: Direction for current flowing into an IC is positive (no mark).

- 1: Typical value is one at  $Ta = 25^{\circ}C$ .
- 2: C<sub>1</sub>, C<sub>0</sub> are periodically sampled and are not 100% tested.



# M5M5256DFP, VP-55LL, -70LL, -70LLI, -55XL,-70XL 262144-BIT (32768-WORD BY 8-BIT) CMOS STATIC RAM

# $\textbf{AC ELECTRICAL CHARACTERISTICS} \quad (\ \texttt{Vcc=5V\pm10\%}, \ \ \text{unless otherwise noted} \ )$

## (1) READ CYCLE

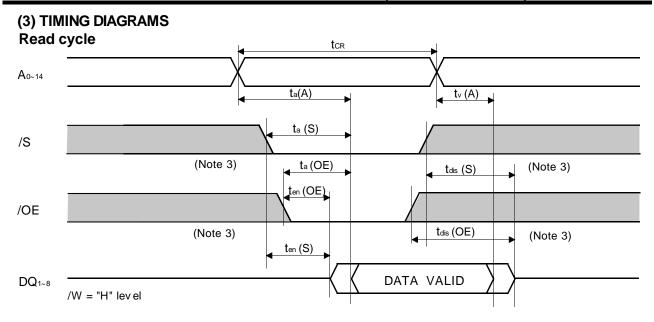
	Parameter		L	mits	nits		
Symbol			, 55XL	-70LL,	Unit		
		Min	Max	Min	Max	•	
tcr	Read cycle time	55		70		ns	
ta(A)	Address access time		55		70	ns	
ta(S)	Chip select access time		55		70	ns	
ta(OE)	Output enable access time		30		35	ns	
tdis(S)	Output disable time after /S high		20		25	ns	
tdis(OE)	Output disable time after /OE high		20		25	ns	
ten(S)	Output enable time after /S low	5		5		ns	
ten(OE)	Output enable time after /OE low	5		5		ns	
t∨(A)	Data valid time after address	10		10		ns	

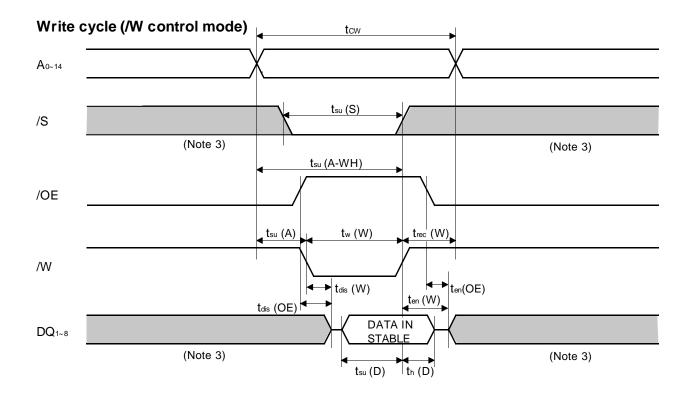
### (2) WRITE CYCLE

	Parameter		Limits				
Oa.la a.l			-55LL, -55XL		-70LL,-70LLI,		
Symbol					-70 XL		
		Min	Max	Min	Max		
tcw	Write cycle time	55		70		ns	
t <sub>w</sub> (W)	Write pulse width	40		50		ns	
tsu(A)	Address setup time	0		0		ns	
tsu(A-WH)	Address setup time with respect to /W high	50		65		ns	
tsu(S)	Chip select setup time	50		65		ns	
tsu(D)	Data setup time	25		30		ns	
t <sub>h</sub> (D)	Data hold time	0		0		ns	
t <sub>rec</sub> (W)	Write recovery time	0		0		ns	
tdis(W)	Output disable time from /W low		20		25	ns	
tdis(OE)	Output disable time from /OE high		20		25	ns	
ten(W)	Output enable time from /W high	5		5		ns	
ten(OE)	Output enable time from /OE low	5		5		ns	



# M5M5256DFP,VP-55LL,-70LL,-70LLI, -55XL,-70XL 262144-BIT (32768-WORD BY 8-BIT) CMOS STATIC RAM



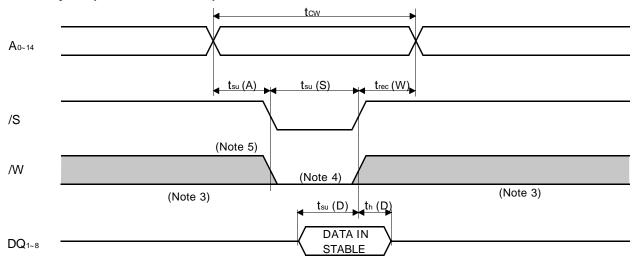




# M5M5256DFP,VP-55LL,-70LL,-70LLI, -55XL,-70XL

262144-BIT (32768-WORD BY 8-BIT) CMOS STATIC RAM

### Write cycle (/S control mode)



Note 3: Hatching indicates the state is "don't care".

4: Writing is executed in overlap of /S and /W low.

5: If /W goes low simultaneously with or prior to /S, the outputs remain in the high impedance state.

6: Don't apply inverted phase signal externally when DQ pin is output mode.

7: ten, tdis are periodically sampled and are not 100% tested.

### (4) MEASUREMENT CONDITIONS

Input pulse level ......  $V_{IH}=2.4V, V_{IL}=0.6V$ 

Input rise and fall time ..... 5ns

Reference level ...... VoH=VoL=1.5V

Output load ...... Fig.1 CL=50pF (-55LL,-55XL)

CL=100pF (-70LL,-70LLI,-70XL)

CL=5pF (for ten,tdis)

Transition is measured ±500mV from steady

state voltage. (for ten,tdis)

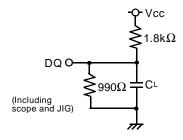


Fig.1 Output load

# M5M5256DFP,VP-55LL,-70LL,-70LLI, -55XL,-70XL 262144-BIT (32768-WORD BY 8-BIT) CMOS STATIC RAM

### **POWER DOWN CHARACTERISTICS**

(1) ELECTRICAL CHARACTERISTICS ( Vcc=5V±10%, unless otherwise noted)

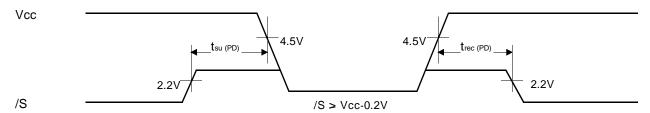
0	Б.,	<b>-</b> .	. 1141		Limits			
Symbol	Parameter	l est co	onditions	3	Min	Тур	Max	Unit
Vcc (PD)	Power down supply voltage			2			V	
		2.2V < Vcc(PD)			2.2			V
VI (/S)	Chip select input /S	2V< Vcc(PD) ≤ 2.2V				VCC(PD)		V
	Power down supply current	Vcc = 3V,/S > Vcc-0.2V, Other inputs=0~Vcc	~25°C	-LL,-LLI			1	
				-XL		0.05	0.2	
			~40°C	-LL,-LLI			3	
ICC (PD)				-XL			0.6	μA
				-LL,-LLI			10	
			~70°C	-XL			2	
			~85°C	-LLI			20	

(2) TIMING REQUIREMENTS ( Vcc=5V±10%, unless otherwise noted )

0 1 1						
Symbol	Parameter	Test conditions	Min	Тур	Max	Unit
tsu (PD)	Power down set up time		0			ns
trec (PD)	Power down recovery time		tCR			ns

## (3) POWER DOWN CHARACTERISTICS

#### /S control mode





**RENESAS LSIs** 

# M5M5256DFP, VP-55LL, -70LL, -70LLI,

-55XL,-70XL

262144-BIT (32768-WORD BY 8-BIT) CMOS STATIC RAM

# Renesas Technology Corp.

Nippon Bldg.,6-2,Otemachi 2-chome,Chiyoda-ku,Tokyo,100-0004 Japan

Keep safety first in your circuit designs!

Renesas Technology Corporation puts the maximum effort into making semiconductor products better and more reliable, but there is always the possibility that trouble may occur with them. Trouble with semiconductors may lead to personal injury, fire or property damage. Remember to give due consideration to safety when making your circuit designs, with appropriate measures such as (i) placement of substitutive, auxiliary circuits, (ii) use of nonflammable material or (iii) prevention against any malfunction or mishap.

- Notes regarding these materials

  These materials are intended as a reference to assist our customers in the selection of the Renesas Technology Corporation product best suited to the customer's application; they do not convey any license under any intellectual property rights, or any other rights, belonging to Renesas Technology Corporation or a third party.

  Renesas Technology Corporation assumes no responsibility for any damage, or infringement of any third-party's rights, originating in the use of any product data, diagrams, charts, programs, algorithms, or circuit application examples contained in these materials, including product data, diagrams, charts, programs and algorithms represents information on products at the time of publication of these materials, and are subject to change by Renesas Technology Corporation without notice due to product improvements or other reasons. It is therefore recommended that customers contact Renesas Technology Corporation or an authorized Renesas Technology Corporation product distributor for the latest product information before purchasing a product listed herein.

  The information described here may contain technical inaccuracies or typographical errors.

  Renesas Technology Corporation assumes no responsibility for any damage, liability, or other loss rising from these inaccuracies or errors.

  Please also pay attention to information published by Renesas Technology Corporation by various means, including the Renesas Technology Corporation Semiconductor home page (http://www.renesas.com).

  When using any or all of the information contained in these materials, including product data, diagrams, charts, programs, and algorithms, please be sure to evaluate all information as a total system before making a final decision on the applicability of the information and products. Renesas Technology Corporation assumes no responsibility for any damage, liability or other loss resulting from

- before making a final decision on the applicability of the information and products. Renesas Technology Corporation assumes no responsibility for any damage, liability or other loss resulting from the information contained herein.
- the information contained nerein.

  Renessa Technology Corporation semiconductors are not designed or manufactured for use in a device or system that is used under circumstances in which human life is potentially at stake. Please contact Renessa Technology Corporation or an authorized Renessa Technology Corporation product distributor when considering the use of a product contained herein for any specific purposes, such as apparatus or systems for transportation, vehicular, medical, aerospace, nuclear, or undersea repeater use.

  The prior written approval of Renessa Technology Corporation is necessary to reprint or reproduce in whole or in part these materials.

  If these products or technologies are subject to the Japanese export control restrictions, they must be exported under a license from the Japanese government and cannot be imported into a country
- other than the approved destination.
- Any diversion or reexport contrary to the export control laws and regulations of Japan and/or the country of destination is prohibited. Please contact Renesas Technology Corporation for further details on these materials or the products contained therein.

**KENESAS** Renesas Technology Corp.

REJ03C0055 © 2003 Renesas Technology Corp. New publication, effective Feb 2004. Specifications subject to change without notice